

Understanding HD & 3G-SDI Video

EYE

EYE DIAGRAM
The eye diagram is constructed by overlaying portions of the sampled data stream until enough data transitions produce the familiar display. A unit interval (U) is defined as the time between two adjacent signal transitions. The reciprocal of clock frequency, U , is 3.7 ns for digital component 525 (SDI 25M), 673.4 ps for digital high-definition (SDI 292) and 336.7 ps for 3G-SDI serial digital (SDI 424M) as shown in Table 1. A serial receiver determines if the signal is "high" or "low" in the center of each eye, and detects the serial data. As noise and jitter in the signal increase through the serial transmission channel, the best decision point is in the center of the eye, although some receivers select a point at a fixed time after each transition point. Any effect which closes the eye may reduce the usefulness of the received signal.

SDI standard 424M (3G-SDI), 292 (High Definition HD) and 250M (Standard Definition SD) defines a range of specifications for the physical layer for the eye diagram. The DC offset is defined by the mid-amplitude point of the signal and should be 0.0 V ± 0.5 V. The amplitude of the signal is specified as 800 mV ± 10% Signal

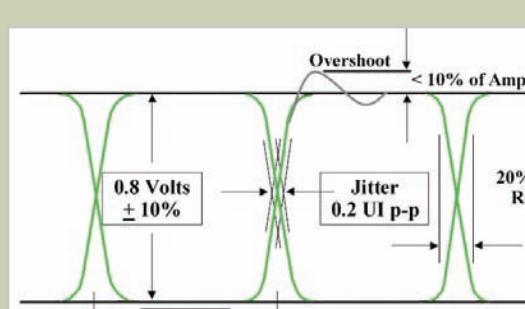
amplitude is important because of its relation to noise, and because the receiver estimates the required high-frequency compensation (equalization) based on the remaining high-clock frequency as the signal arrives. Incorrect amplitude at the sending end could result in an incorrect equalization applied at the receiving end, thus causing signal distortions. Overshoot of the rising and falling edge should not exceed 10% of the waveform for SDI (Serial Digital Interface) formats. Overshoot could be the result of incorrect rise time, but is more likely caused by impedance discontinuities or poor return loss at the receiving or sending terminations. The rise and fall times determine the 20% and 80% points shown in greater than 135 ps and shall not differ by more than 50 ps for 3G-SDI, shall be no greater than 270 ps and shall not differ by more than 100 ps for HD and shall be no less than 0.4 ns, no greater than 1.5 ns, and shall not differ by more than 0.5 ns for SD as summarized in Table 2. Incorrect rise time could cause signal distortions such as ringing and overshoot, or, if too slow, could reduce the time available for sampling within the eye.

Unit Interval	HD (292)	SD (25M)	SD-SDI (424M)
3.7ns	673.4ps	336.7ps	

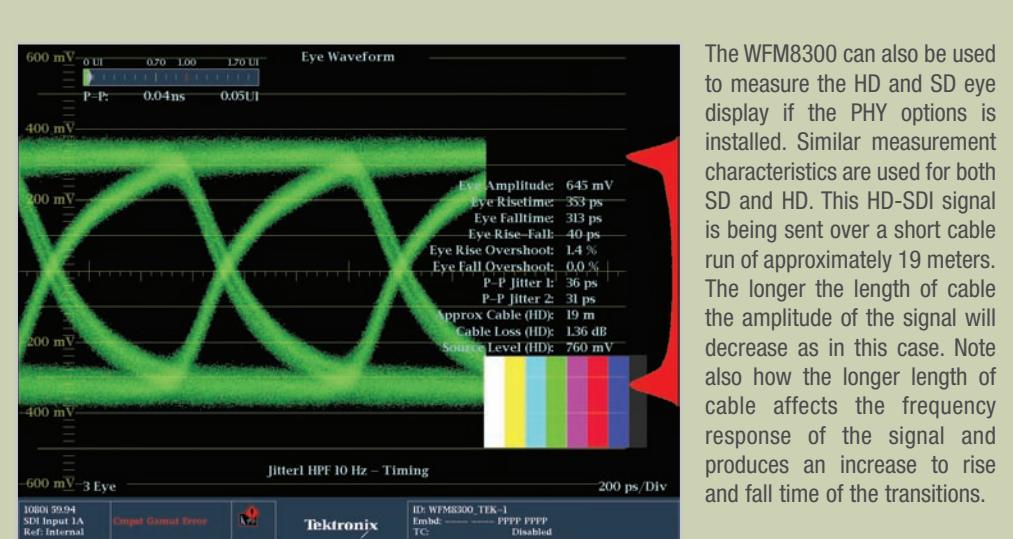
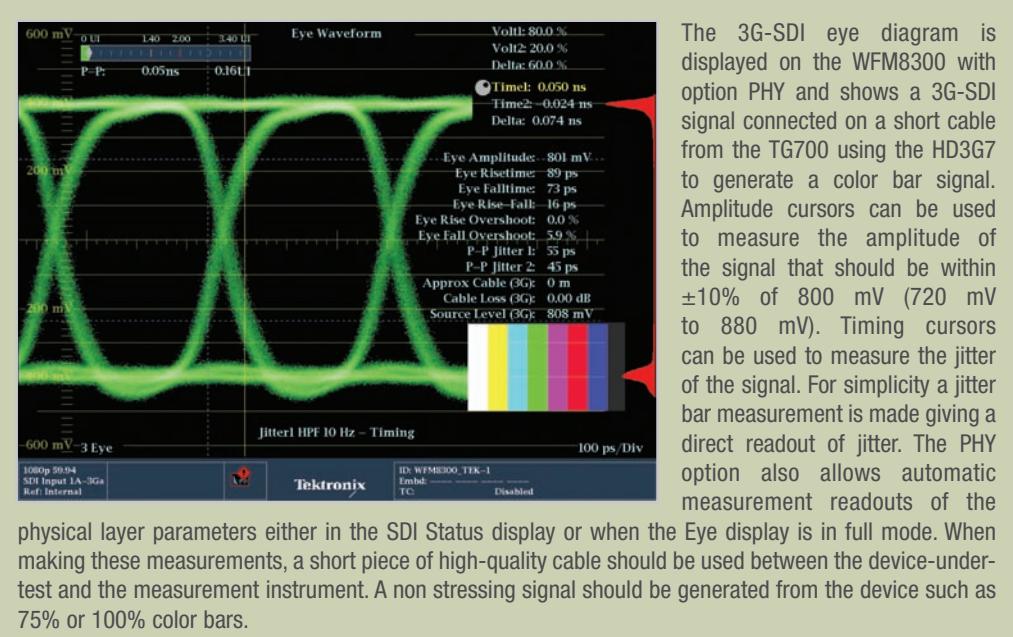
Table 1.

Rise/Fall Time	HD (292)	SD (25M)	SD-SDI (424M)
Shall be no less than 1.4 ns, no greater than 2.7 ns and shall not differ by more than 100 ps	0.8 Volts ± 10%	0.8 Volts ± 10%	0.8 Volts ± 10%

Table 2.



Maintaining a digital system within these specifications guarantees reliable transmission of this signal. Digital systems will work outside this specification, but will fail at some point. It is difficult to determine the failure point, so it is critical to maintain the health of the physical layer to prevent the system from failing off the digital cliff.



SDI recommended practice RP184 has a set of definitions and measurement procedures for the measurement of jitter. SMPTE 424M, 292 and 250M defines a set of frequency limits based on this recommended practice.

f1 = 10 Hz = Timing jitter lower band edge
f3 = 1 kHz = Alignment jitter lower band edge for SD
f3 = 100 kHz = Alignment jitter lower band edge for HD & 3G-SDI
f4 > 1/10 the clock rate = Upper band edge

Jitter is defined as the variation of a digital signal's significant instants (such as transition points) from their ideal positions in time. Jitter can cause the recovered clock and the data to become momentarily misaligned in time. Data may be misinterpreted (latched at the wrong time) if this misalignment becomes great enough.

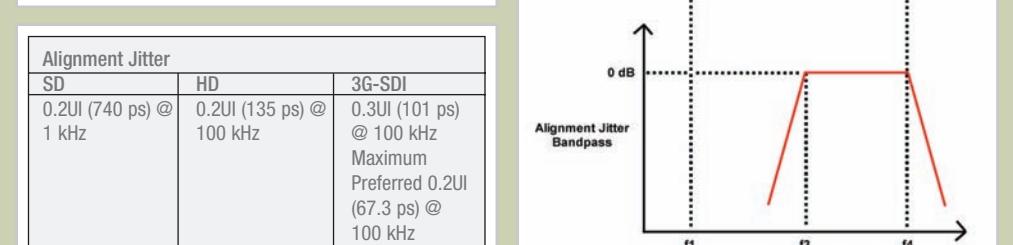
Timing jitter is defined as the variation in time of the significant instances (such as zero crossings) of a digital signal relative to a jitter-free clock above some low frequency typically 10 Hz. It is preferable to use the original reference clock, but it is not usually available, so a heavily averaged oscillator in the measurement circuit can be used (Table 3).

Alignment jitter or relative jitter, is defined as the variation in time of the significant instants (such as zero crossings) of a digital signal itself. To a hypothetical clock below its recovery threshold. This recovered clock will track in the signal up to its upper clock recovery bandwidth, typically 1 kHz to 100 kHz. Measured alignment jitter includes those terms above this frequency. Alignment jitter shows signal-to-latch clock.



The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.



The SDI Check Field is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.



The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to be transmitted successfully then tearing of the picture will be observed on a display.

SDI CHECK FIELD

The SDI Check Field (also known as a "pathological field") is a full-field test signal and therefore must be performed out-of-service. It is specified to have a maximum amount of low-frequency energy, after scrambling, in two separate parts of the field. Statistically, this low-frequency energy occurs about once per frame. The check field is generated by operating by generating a sequence of 10 rows followed by a 1 (or 19 if 1's is followed by 0). This occurs about once per field as the scrambler attains the required starting condition, and when it occurs it will persist for the full line and terminate with the EAV packet. This sequence produces a high DC component that stresses the analog capabilities of the equipment and

transmission system handling the signal. The other part of the signal is designed to check phase-locked loop performance with an occasional signal consisting of 20 0's followed by 20 1's. This provides a minimum number of zero crossings for clock extraction. The part of the test signal may appear at the output of the display as a solid gray, with luma set to 100% and chroma channels set to 200%. If the SDI-check field fails to

